WEST Search History

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DATE: Tuesday, March 01, 2005

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		DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ	
☐	L20	L19 and test pattern generat$	39
☐	L19	L18 and 324/$.ccls.	320
☐	L18	L17 and (BIST or self test)	5344
☐	L17	L1 and memory	220180
☐	L16	l4 and 324/$.ccls.	114
☐	L6	L5 and inverter	147
☐	L5	L4 and test data	430
☐	L4	L3 and memory	890
☐	L3	L2 AND clock	1170
☐	L2	L1 and test pattern generat$	1933
☐	L1	(IC or integrated circuit)	1469205

END OF SEARCH HISTORY

For 10/647506